

N and P Channel Enhancement Mode Power MOSFET

Description

This Product uses advanced trench technology MOSFETs to provide excellent $R_{DS(ON)}$ and low gate charge. The complementary MOSFETs may be used to form a level shifted high side switch, and for a host of other applications.

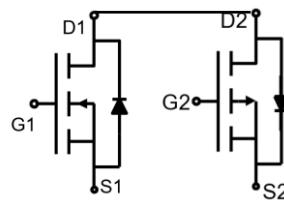
General Features

- NMOS
- V_{DS} 60V
- I_D (at $V_{GS} = 10V$) 18A
- $R_{DS(ON)}$ (at $V_{GS} = 10V$) < 35mΩ
- $R_{DS(ON)}$ (at $V_{GS} = 4.5V$) < 45mΩ

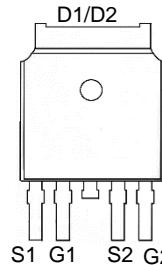
- PMOS
- V_{DS} -60V
- I_D (at $V_{GS} = -10V$) -18A
- $R_{DS(ON)}$ (at $V_{GS} = -10V$) < 45mΩ
- RoHS Compliant

Application

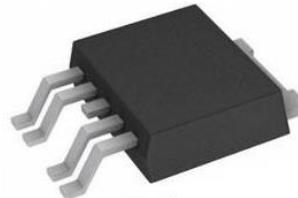
- Power switch
- DC/DC converters



Schematic diagram



Marking and pin assignment



TO-252-4

Device	Package	Marking	Packaging
G18NP06Y	TO-252-4	G18NP06	2500pcs/Reel

Absolute Maximum Ratings $T_C = 25^\circ\text{C}$, unless otherwise noted

Parameter	Symbol	NMOS	PMOS	Unit
Drain-Source Voltage	V_{DS}	60	-60	V
Continuous Drain Current	I_D	18	-18	A
Pulsed Drain Current (note1)	I_{DM}	72	-72	A
Gate-Source Voltage	V_{GS}	± 20	± 20	V
Power Dissipation	P_D	45	50	W
Single pulse avalanche energy (note3)	E_{AS}	20	56	mJ
Operating Junction and Storage Temperature Range	T_J, T_{stg}	-55 To 150	-55 To 150	°C

Thermal Resistance

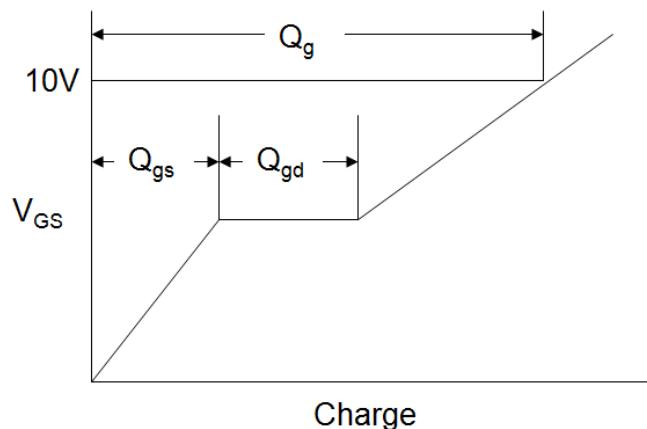
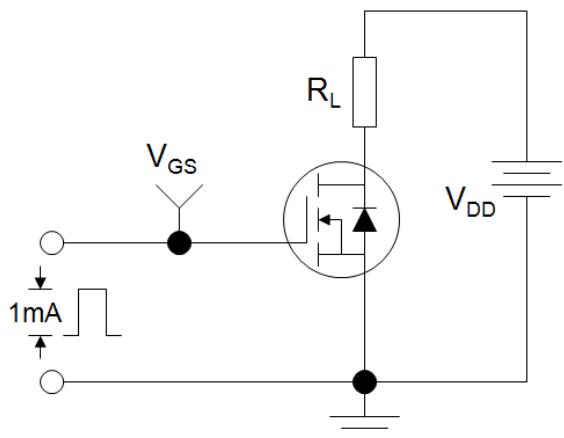
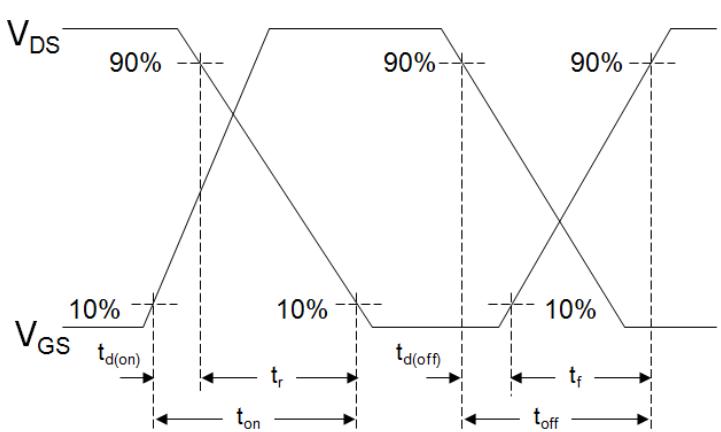
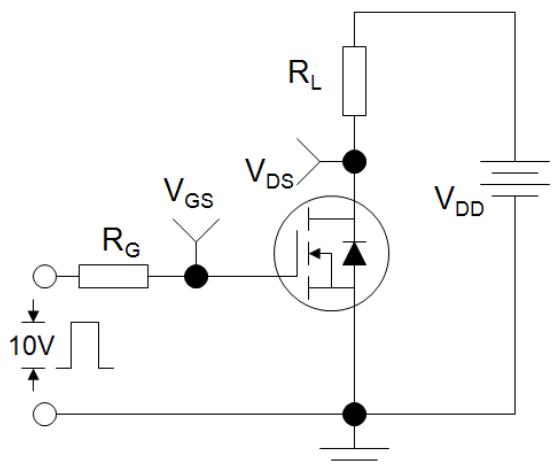
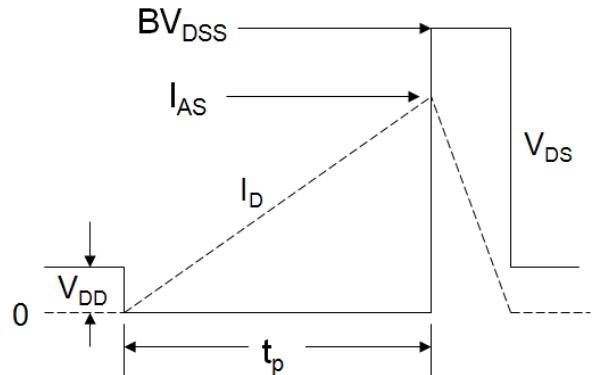
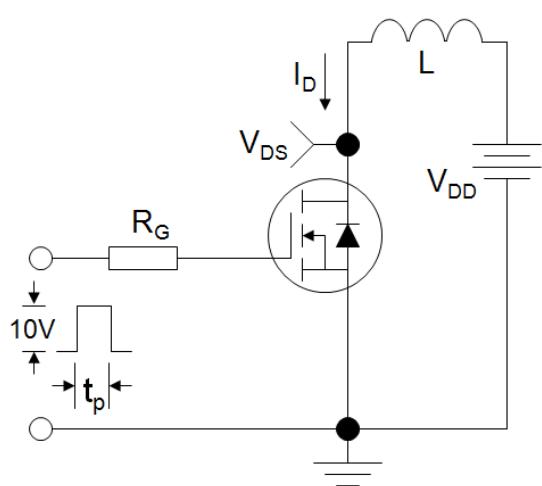
Parameter	Symbol	NMOS	PMOS	Unit
Thermal Resistance, Junction-to-Case	R_{thJC}	3.3	3.2	°C/W

NMOS Specifications $T_J = 25^\circ\text{C}$, unless otherwise noted

Parameter	Symbol	Test Conditions	Value			Unit
			Min.	Typ.	Max.	
Static Parameters						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = 250\mu\text{A}$	60	--	--	V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{\text{DS}} = 60\text{V}, V_{\text{GS}} = 0\text{V}, T_J = 25^\circ\text{C}$	--	--	1	μA
Gate-Source Leakage	I_{GSS}	$V_{\text{GS}} = \pm 20\text{V}$	--	--	± 100	nA
Gate-Source Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}} = V_{\text{GS}}, I_D = 250\mu\text{A}$	1.0	1.5	2.5	V
Drain-Source On-Resistance	$R_{\text{DS}(\text{on})}$	$V_{\text{GS}} = 10\text{V}, I_D = 12\text{A}$	--	26	35	$\text{m}\Omega$
		$V_{\text{GS}} = 4.5\text{V}, I_D = 12\text{A}$	--	30	45	
Forward Transconductance	g_{FS}	$V_{\text{DS}}=5\text{V}, I_D=6\text{A}$	--	12.5	--	S
Dynamic Parameters						
Input Capacitance	C_{iss}	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 30\text{V}, f = 1.0\text{MHz}$	--	1350	--	pF
Output Capacitance	C_{oss}		--	54	--	
Reverse Transfer Capacitance	C_{rss}		--	51	--	
Total Gate Charge	Q_g	$V_{\text{DS}} = 30\text{V}, I_D = 5\text{A}, V_{\text{GS}} = 10\text{V}$	--	22	--	nC
Gate-Source Charge	Q_{gs}		--	3.3	--	
Gate-Drain Charge	Q_{gd}		--	5.2	--	
Turn-on Delay Time	$t_{\text{d}(\text{on})}$	$V_{\text{DD}} = 30\text{V}, I_D = 5\text{A}, R_G = 3\Omega$	--	5.2	--	ns
Turn-on Rise Time	t_r		--	3	--	
Turn-off Delay Time	$t_{\text{d}(\text{off})}$		--	17	--	
Turn-off Fall Time	t_f		--	2.5	--	
Drain-Source Body Diode Characteristics						
Body Diode Voltage	V_{SD}	$T_J = 25^\circ\text{C}, I_{\text{SD}} = 12\text{A}, V_{\text{GS}} = 0\text{V}$	--	--	1.2	V
Continuous Body Diode Current	I_S	$T_C = 25^\circ\text{C}$	--	--	18	A
Reverse Recovery Time	T_{rr}	$I_S = 12\text{A}, V_{\text{GS}} = 0\text{V}$ $dI/dt = 100\text{A}/\mu\text{s}$	--	29	--	ns
Reverse Recovery Charge	Q_{rr}		--	50	--	nc

Notes

1. Repetitive Rating: Pulse width limited by maximum junction temperature
2. Identical low side and high side switch with identical R_G
3. EAS condition : $T_J=25^\circ\text{C}$, $V_{\text{DD}}=50\text{V}$, $V_{\text{G}}=10\text{V}$, $L=0.5\text{mH}$, $R_g=25\Omega$

Gate Charge Test Circuit

Switch Time Test Circuit

EAS Test Circuit


NMOS Typical Characteristics $T_J = 25^\circ\text{C}$, unless otherwise noted

Figure 1. Output Characteristics

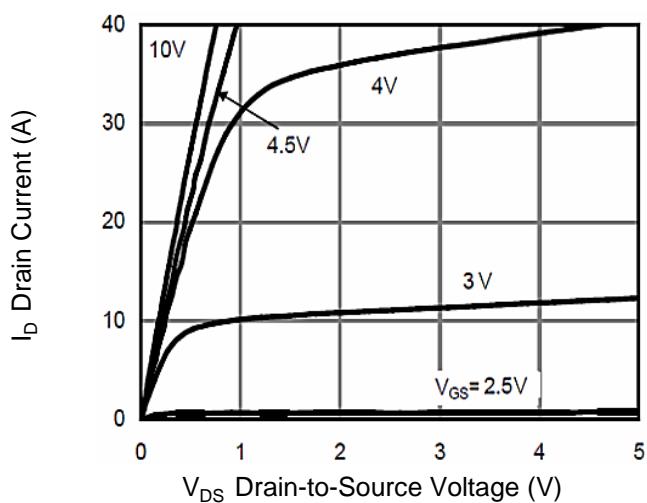


Figure 2. Transfer Characteristics

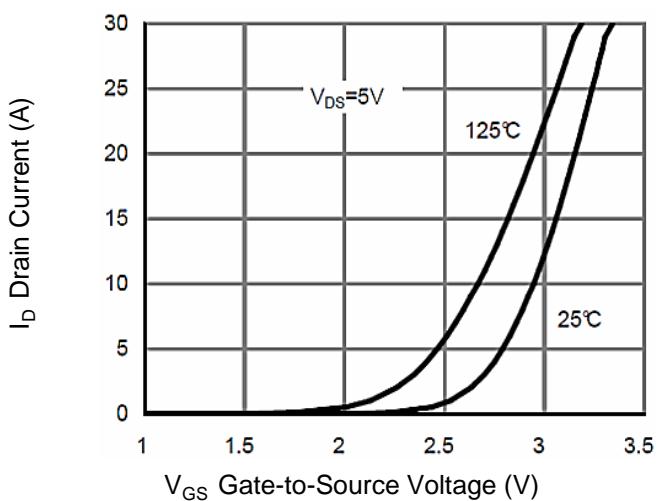


Figure 3. Drain-Source On-Resistance

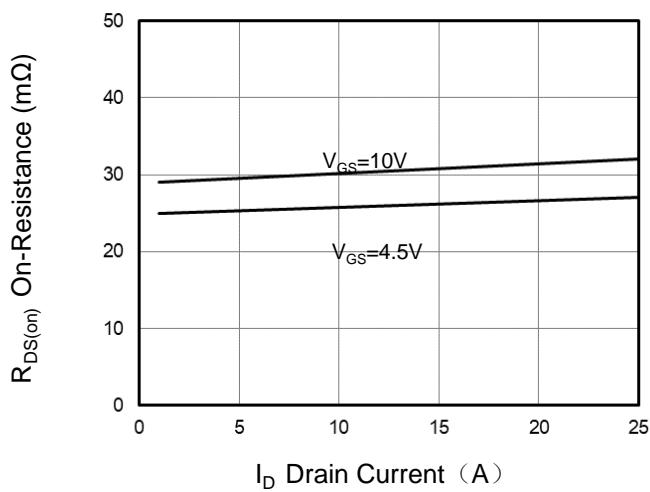


Figure 4. Gate Charge

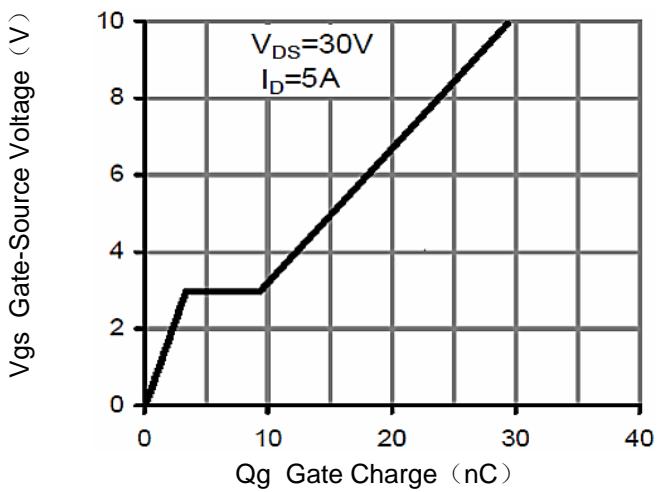


Figure 5. Capacitance

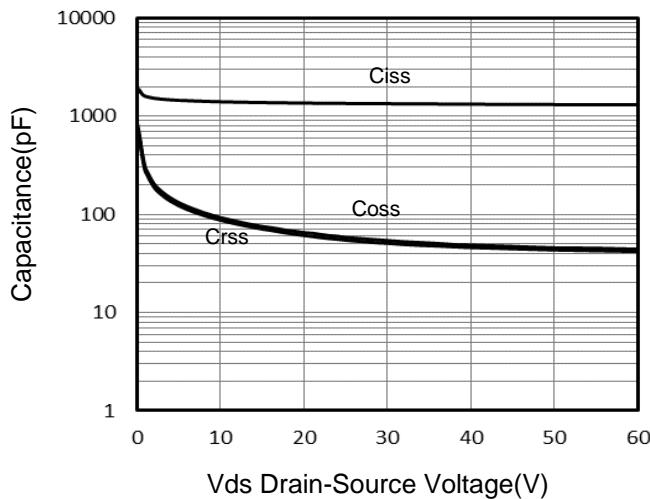
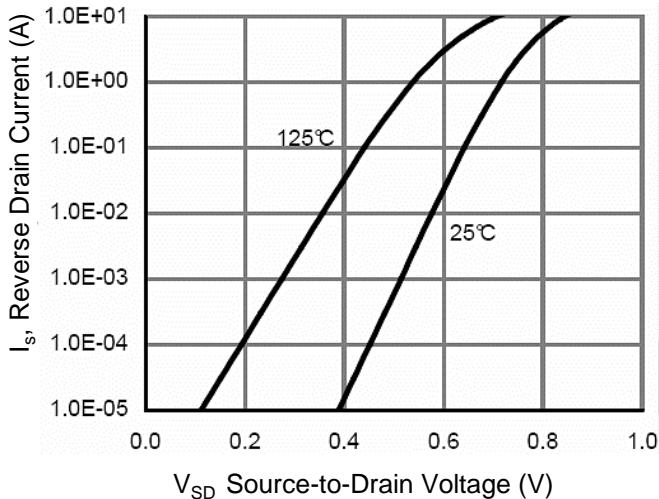


Figure 6. Source-Drain Diode Forward



NMOS Typical Characteristics $T_J = 25^{\circ}\text{C}$, unless otherwise noted

Figure 7. Drain-Source On-Resistance

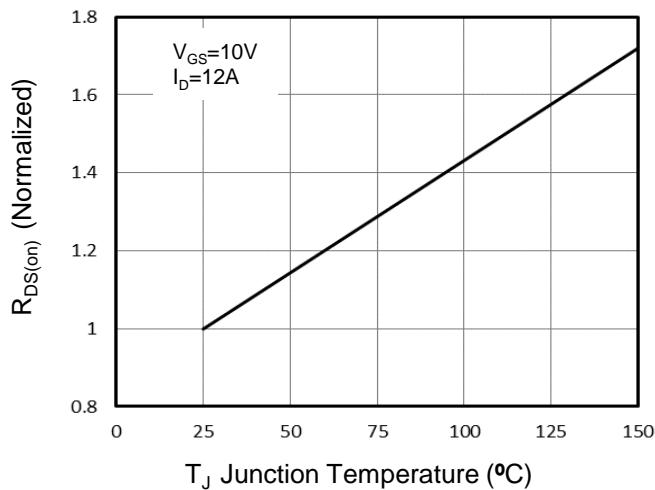


Figure 8. Safe Operation Area

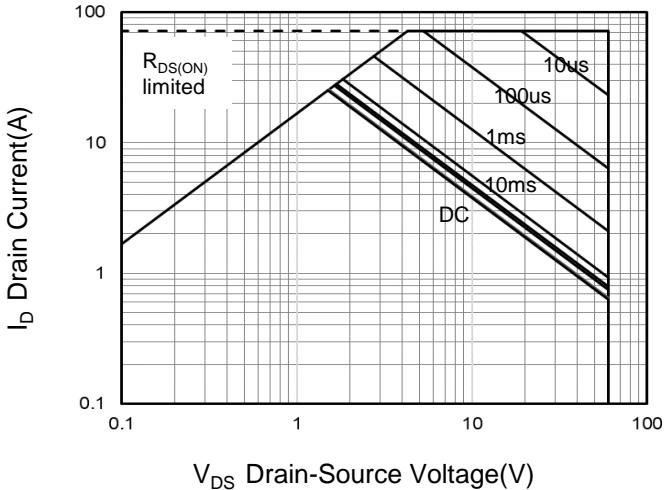
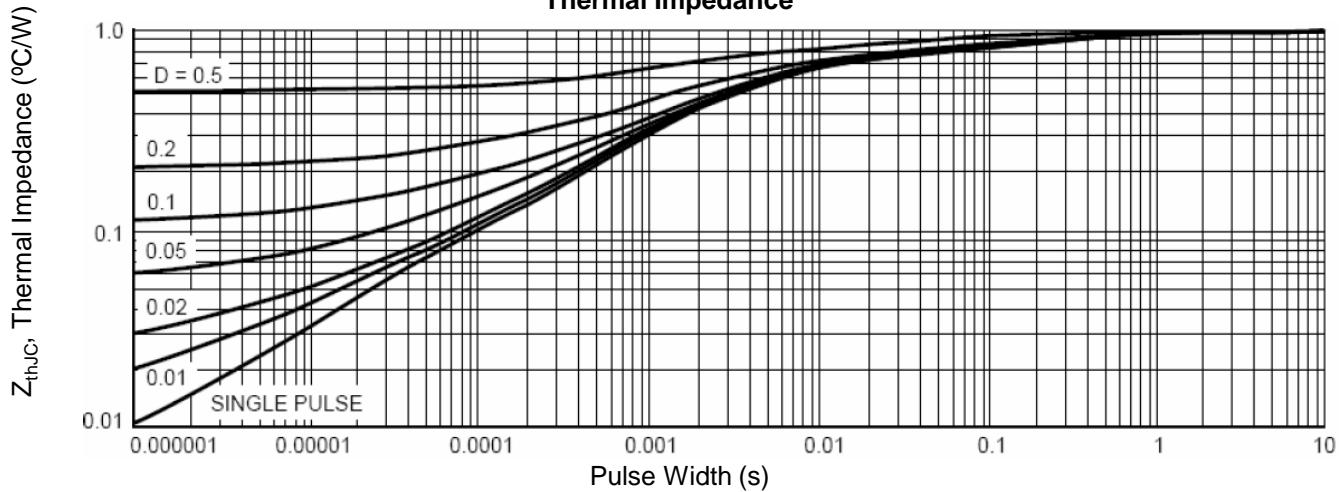


Figure 9. Normalized Maximum Transient Thermal Impedance

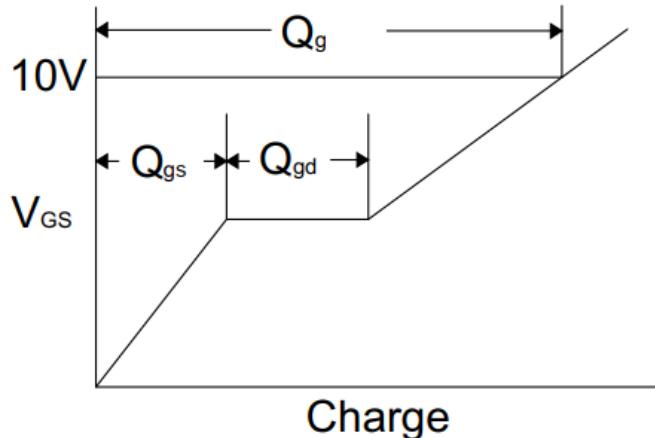
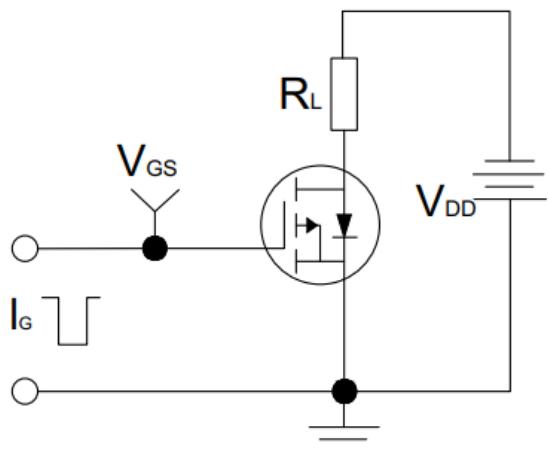
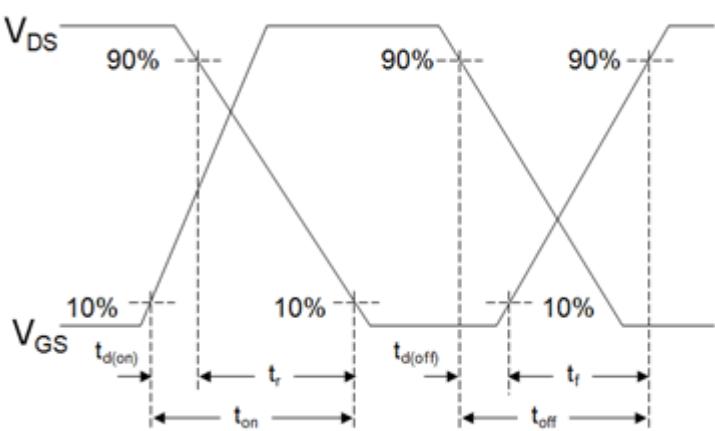
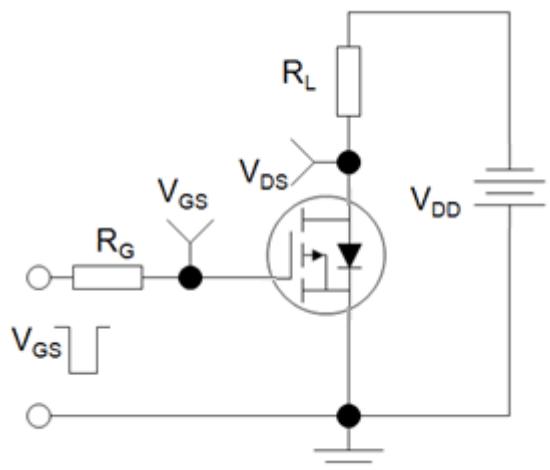
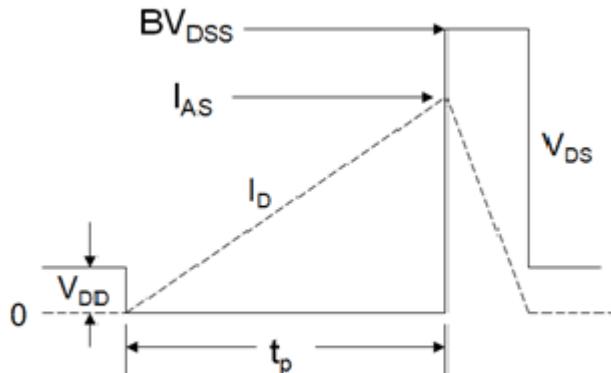
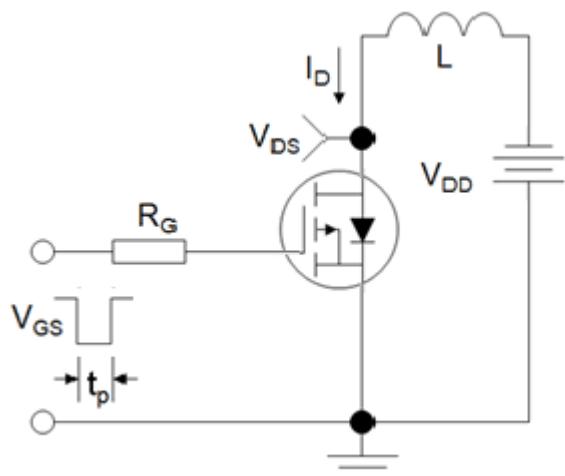


PMOS Specifications $T_J = 25^\circ\text{C}$, unless otherwise noted

Parameter	Symbol	Test Conditions	Value			Unit
			Min.	Typ.	Max.	
Static Parameters						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = -250\mu\text{A}$	-60	--	--	V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{\text{DS}} = -60\text{V}, V_{\text{GS}} = 0\text{V}, T_J = 25^\circ\text{C}$	--	--	-1	μA
Gate-Source Leakage	I_{GSS}	$V_{\text{GS}} = \pm 20\text{V}$	--	--	± 100	nA
Gate-Source Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}} = V_{\text{GS}}, I_D = -250\mu\text{A}$	-1.5	-2.5	-3.5	V
Drain-Source On-Resistance	$R_{\text{DS}(\text{on})}$	$V_{\text{GS}} = -10\text{V}, I_D = -12\text{A}$	--	33	45	$\text{m}\Omega$
Forward Transconductance	g_{FS}	$V_{\text{DS}} = -5\text{V}, I_D = -12\text{A}$	--	9	--	S
Dynamic Parameters						
Input Capacitance	C_{iss}	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = -30\text{V}, f = 1.0\text{MHz}$	--	2610	--	pF
Output Capacitance	C_{oss}		--	114	--	
Reverse Transfer Capacitance	C_{rss}		--	111	--	
Total Gate Charge	Q_g	$V_{\text{DD}} = -30\text{V}, I_D = -5\text{A}, V_{\text{GS}} = -10\text{V}$	--	25	--	nC
Gate-Source Charge	Q_{gs}		--	4	--	
Gate-Drain Charge	Q_{gd}		--	7	--	
Turn-on Delay Time	$t_{\text{d}(\text{on})}$	$V_{\text{DD}} = -30\text{V}, I_D = -5\text{A}, R_G = 6\Omega$	--	15	--	ns
Turn-on Rise Time	t_r		--	58	--	
Turn-off Delay Time	$t_{\text{d}(\text{off})}$		--	30	--	
Turn-off Fall Time	t_f		--	36	--	
Drain-Source Body Diode Characteristics						
Continuous Body Diode Current	I_S	$T_C = 25^\circ\text{C}$	--	--	-18	A
Body Diode Voltage	V_{SD}	$T_J = 25^\circ\text{C}, I_{\text{SD}} = -12\text{A}, V_{\text{GS}} = 0\text{V}$	--	--	-1.2	V
Reverse Recovery Time	T_{rr}	$I_S = -5\text{A}, V_{\text{GS}} = 0\text{V}$ $dI/dt = -100\text{A/us}$	--	20	--	ns
Reverse Recovery Charge	Q_{rr}		--	19	--	nC

Notes

1. Repetitive Rating: Pulse width limited by maximum junction temperature
2. Identical low side and high side switch with identical R_G
3. EAS condition : $T_J=25^\circ\text{C}$, $V_{\text{DD}}=-50\text{V}$, $V_{\text{G}}=-10\text{V}$, $L=0.5\text{mH}$, $R_g=25\Omega$

Gate Charge Test Circuit

Switch Time Test Circuit

EAS Test Circuit


PMOS Typical Characteristics $T_J = 25^\circ\text{C}$, unless otherwise noted

Figure 1. Output Characteristics

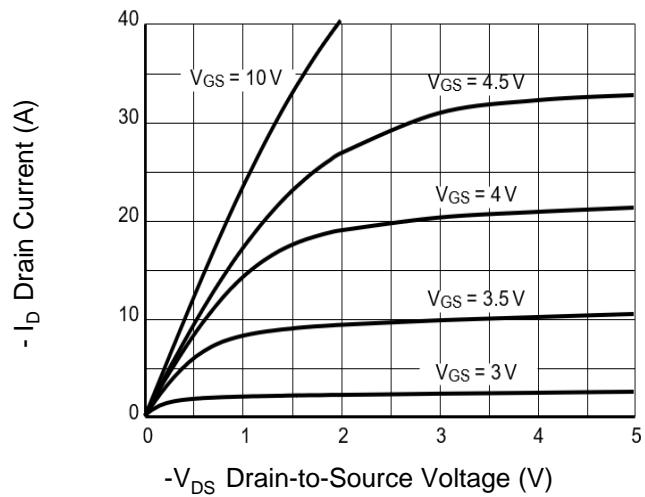


Figure 2. Transfer Characteristics

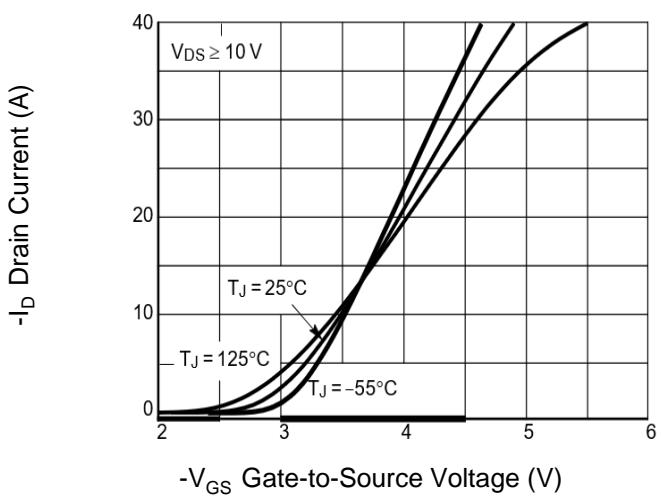


Figure 3.Rdson-Drain Current

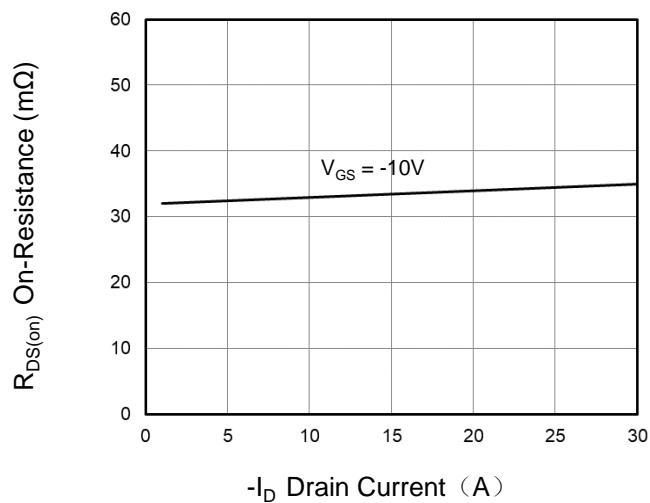


Figure 4. Gate Charge

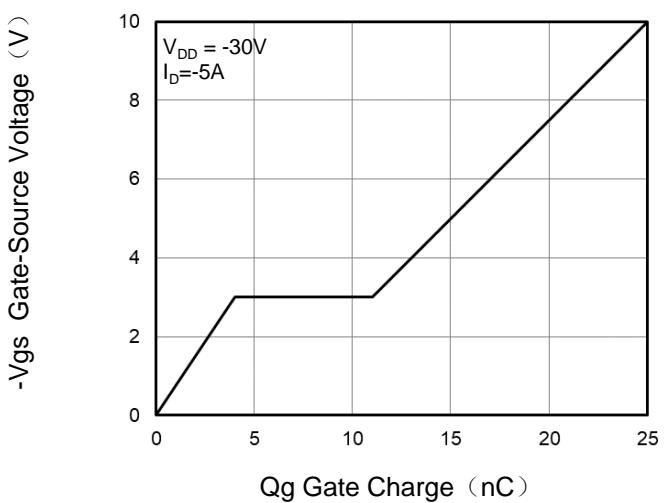


Figure 5. Capacitance

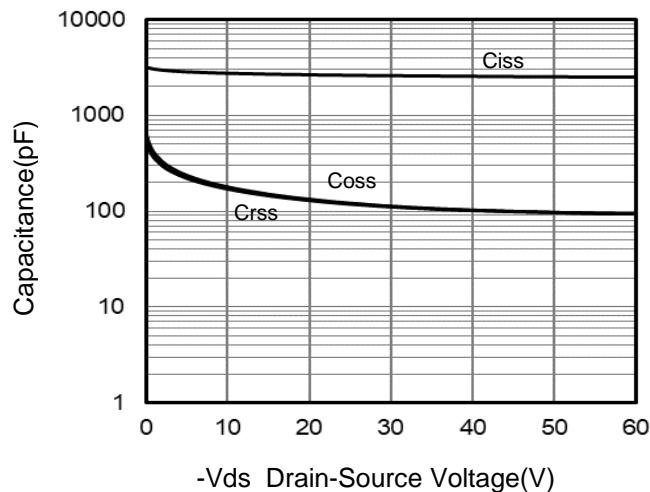
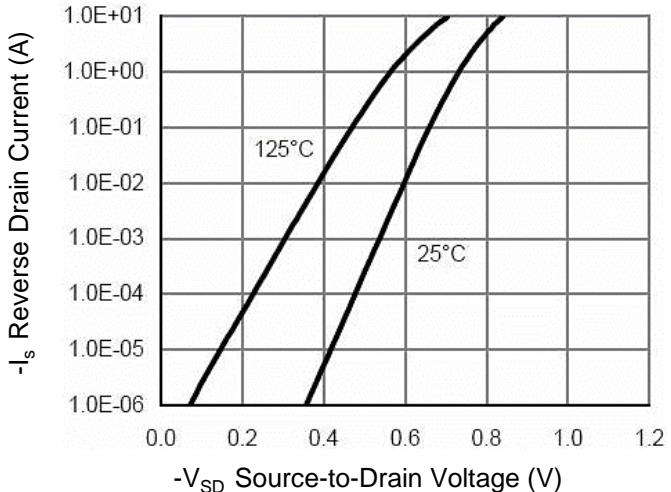


Figure 6. Source-Drain Diode Forward



PMOS Typical Characteristics $T_J = 25^{\circ}\text{C}$, unless otherwise noted

Figure 7. Drain-Source On-Resistance

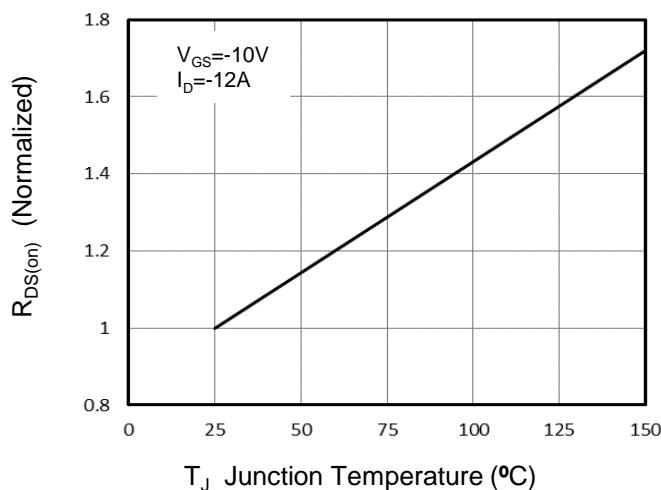


Figure 8. Safe Operation Area

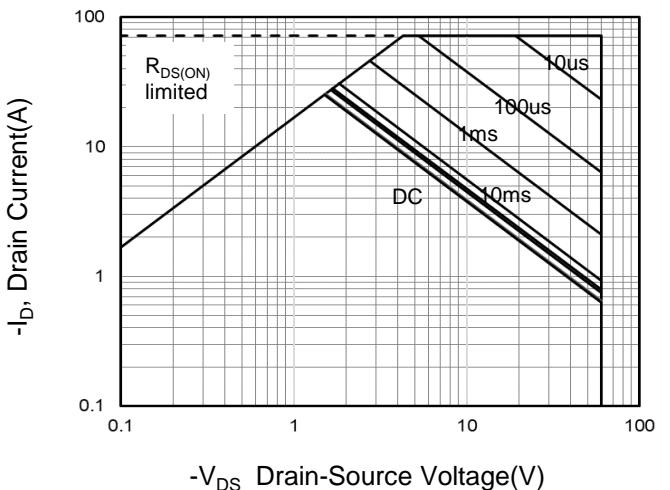
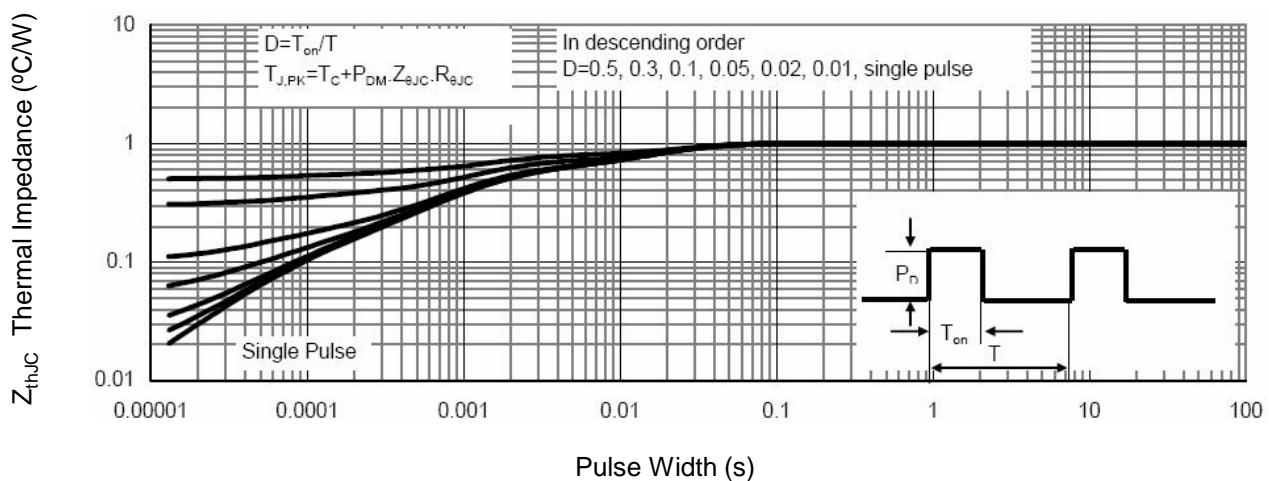
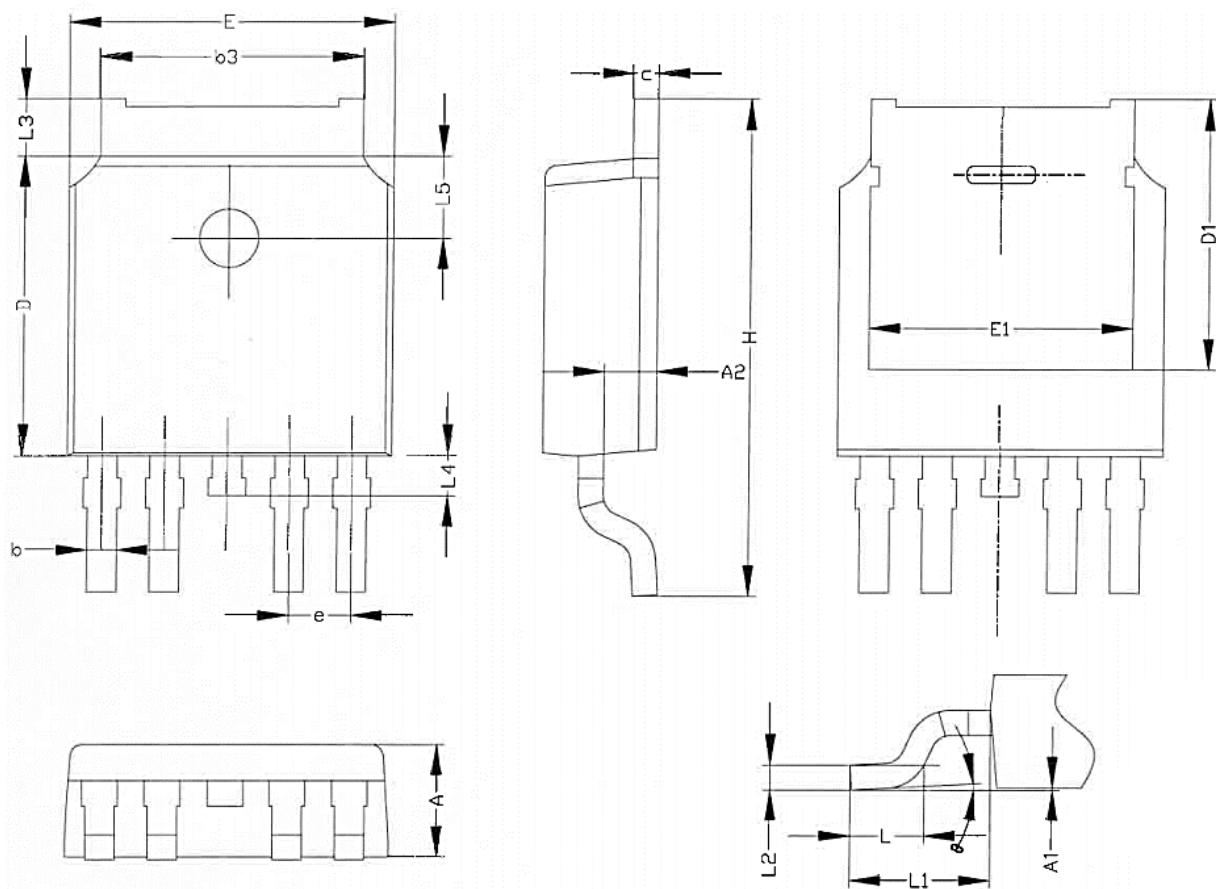


Figure 9. Normalized Maximum Transient Thermal Impedance



TO-252-4 Package Information



SYMBOL	mm		
	MIN	NOM	MAX
A	2.20	2.30	2.38
A1	0.00	-	0.20
A2	0.97	1.07	1.17
b	0.55	0.62	0.70
b3	5.20	5.33	5.46
c	0.43	0.53	0.61
D	5.98	6.10	6.22
D1	5.30REF		
E	6.40	6.60	6.73
E1	5.10	-	-
e	1.27BSC		
H	9.40	10.10	10.50
L	1.38	1.50	1.75
L1	2.90REF		
L2	0.51BSC		
L3	0.88	-	1.28
L4	0.50	-	1.00
L5	1.65	1.80	1.95
θ	0°	-	8°